TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

TC74AC20P,TC74AC20F,TC74AC20FN

Dual 4-Input NAND Gate

The TC74AC20 is an advanced high speed CMOS 4-INPUT NAND GATE fabricated with silicon gate and double-layer metal wiring C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output.

All inputs are equipped with protection circuits against static discharge or transient excess voltage.

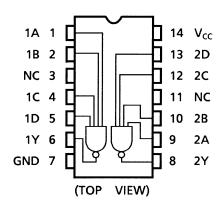
Features

- High speed: $t_{pd} = 4.1$ ns (typ.) at $V_{CC} = 5$ V
- Low power dissipation: $I_{CC} = 4 \mu A (max)$ at $Ta = 25^{\circ}C$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC}$ (min)
- Symmetrical output impedance: |IOH| = IOL = 24 mA (min)

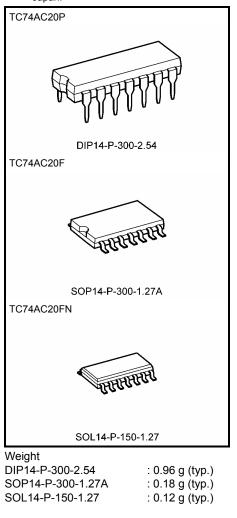
Capability of driving 50 Ω transmission lines.

- Balanced propagation delays: $t_{pLH}\simeq t_{pHL}$
- Wide operating voltage range: V_{CC} (opr) = 2~5.5 V
- Pin and function compatible with 74F20

Pin Assignment

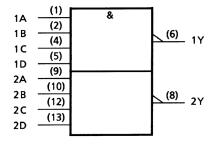


Note: xxxFN (JEDEC SOP) is not available in Japan.



<u>TOSHIBA</u>

IEC Logic Symbol



Truth Table

А	В	С	D	Y
L	Х	Х	Х	Н
х	L	Х	Х	Н
х	Х	L	Х	Н
х	Х	Х	L	Н
Н	Н	Н	Н	L

X: Don't care

Characteristics	Symbol	Rating	Unit
Supply voltage range	V _{CC}	-0.5~7.0	V
DC input voltage	V _{IN}	$-0.5 \sim V_{CC} + 0.5$	V
DC output voltage	Vout	-0.5~V _{CC} + 0.5	V
Input diode current	lık	±20	mA
Output diode current	Іок	±50	mA
DC output current	IOUT	±50	mA
DC V _{CC} /ground current	Icc	±100	mA
Power dissipation	PD	500 (DIP) (Note 2)/180 (SOP)	mW
Storage temperature	T _{stg}	-65~150	°C

Absolute Maximum Ratings (Note 1)

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: 500 mW in the range of Ta = $-40\sim65^{\circ}$ C. From Ta = 65 to 85°C a derating factor of -10 mW/° C should be applied up to 300 mW.

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit	
Supply voltage	V _{CC}	2.0~5.5	V	
Input voltage	V _{IN}	0~V _{CC}	V	
Output voltage	V _{OUT}	0~V _{CC}	V	
Operating temperature	T _{opr}	-40~85	°C	
Input rise and fall time	dt/dV	0~100 (V_{CC} = 3.3 \pm 0.3 V)	ns/V	
	uvuv	0~20 (V_{CC} = 5 \pm 0.5 V)	115/ V	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Electrical Characteristics

DC Characteristics

			Test Condition			$Ta = 25^{\circ}C$		Ta = -40~85°C			
Characteristics Sy	Symbol				V _{CC} (V)	Min	Тур.	Max	Min	Max	Unit
		_		2.0	1.50	_	_	1.50	_		
High-level input voltage	VIH			3.0	2.10	—	—	2.10	—	V	
				5.5	3.85	—	_	3.85	_		
		_		2.0	—	—	0.50		0.50	v	
Low-level input voltage	VIL			3.0	—	—	0.90		0.90		
Ĵ				5.5	_	—	1.65	—	1.65		
	V _{OH}	V _{IN} = V _{IH} or V _{IL}	I _{OH} = -50 μA	2.0	1.9	2.0	—	1.9	—	v	
				3.0	2.9	3.0	—	2.9	—		
High-level output				4.5	4.4	4.5	_	4.4	_		
voltage			$I_{OH} = -4 \text{ mA}$		3.0	2.58	—	—	2.48	—	v
			$I_{OH} = -24 \text{ mA}$		4.5	3.94	—	—	3.80	—	
			$I_{OH} = -75 \text{ mA}$	(Note)	5.5	_	—	_	3.85	_	
	V _{OL}	V _{IN} = VIH	I _{OL} = 50 μA		2.0	—	0.0	0.1		0.1	V
					3.0	—	0.0	0.1		0.1	
Low-level output voltage					4.5	_	0.0	0.1	—	0.1	
			I _{OL} = 12 mA I _{OL} = 24 mA	3.0	—	—	0.36		0.44	v	
					4.5	—	—	0.36		0.44	
			$I_{OL} = 75 \text{ mA}$	(Note)	5.5	_	—	_		1.65	
Input leakage current	I _{IN}	$V_{IN} = V_{CC}$ or GND		5.5	—	—	±0.1	—	±1.0	μA	
Quiescent supply current	ICC	$V_{IN} = V_C$	$V_{IN} = V_{CC}$ or GND		5.5			4.0	_	40.0	μA

Note: This spec indicates the capability of driving 50 Ω transmission lines.

One output should be tested at a time for a 10 ms maximum duration.

AC Characteristics (C_L = 50 pF, R_L = 500 Ω , input: t_r = t_f = 3 ns)

Characteristics	Symbol	Test Condition		Ta = 25°C		Ta = -40~85°C		Unit	
		Test Condition	V _{CC} (V)	Min	Тур.	Max	Min	Max	Offic
Propagation delay time	tpLH		$\textbf{3.3}\pm\textbf{0.3}$	_	6.0	10.0	1.0	11.4	ns
	t _{pHL}		5.0 ± 0.5	—	4.8	7.0	1.0	8.0	
Input capacitance	CIN	_			5	10		10	pF
Power dissipation capacitance	C _{PD} (Note)	_		_	66	_			pF

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

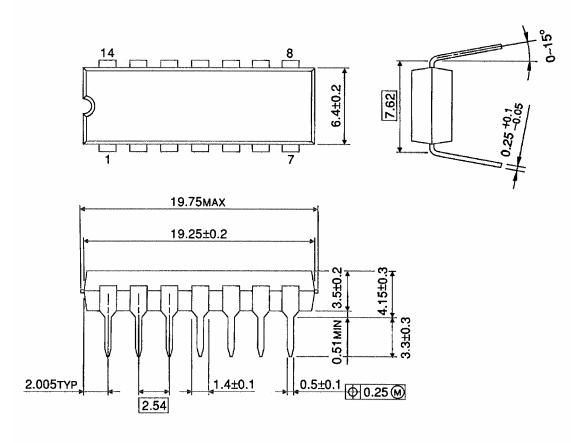
Average operating current can be obtained by the equation:

 I_{CC} (opr) = $C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/2$ (per gate)

Package Dimensions

DIP14-P-300-2.54

Unit : mm

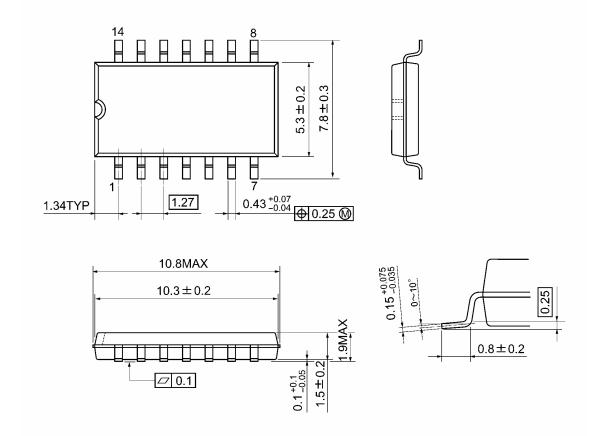


Weight: 0.96 g (typ.)

Package Dimensions

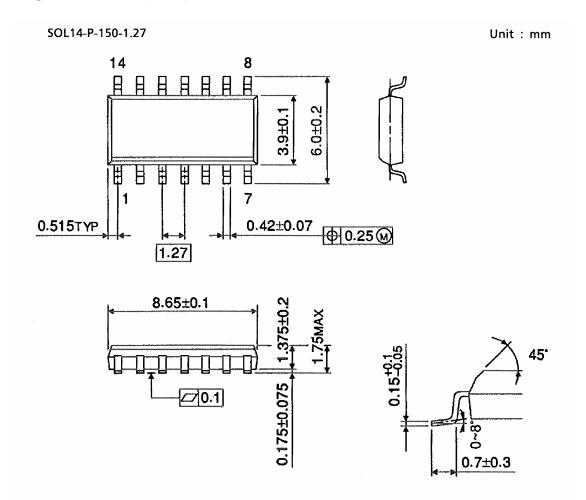
SOP14-P-300-1.27A

Unit: mm



Weight: 0.18 g (typ.)

Package Dimensions (Note)



Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

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20070701-EN GENERAL

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